



Kristina Kutukova is an X-ray application specialist at deepXscan GmbH in Dresden. Her responsibilities include development and demonstration of a broad range applications of high-resolution X-ray imaging. Kristina Kutukova received her double Master degree in Non-Destructive Testing at Dresden International University, Germany, and Tomsk Polytechnic University, Russia, in 2016. Her PhD thesis was targeted on the mechanical robustness of microelectronic products, studying microcrack propagation in on-chip interconnect stacks. More than 5 years she was a research associate in the Department of Microelectronic Materials and Nano-scale Analysis at Fraunhofer Institute for Ceramic Technologies and Systems Dresden, Germany. Her field of research was a high-resolution X-ray imaging, in particular design, development and integration of in-situ and operando setups into X-ray microscopy and nano-XCT systems for a microelectronics and battery applications. Kristina Kutukova is Member of

the Scientific Committee of the European Nanoanalysis Symposium, annually held within the Fall Meeting of the European Materials Research Society (E-MRS).